Search Notes			

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/669,443	LEE, JEONG SIK	
Examiner	Art Unit	
Peter P. Nerbun	3765	

SEARCHED			
Class	Subclass	Date	Examiner
2	181	7/20/2005	PN
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INTERFERENCE SEARCHED			
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SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
None	7/20/2005	PN